

COMPLIANCE ASSESSMENT WITH DIRECTIVE 2014/30/EU

Equipment name:
Part number:

Test report no: CEM
RELEASE:0

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Contents

1 Purpose	3
2 List of standards and tests performed	3
3 Description and features of the equipment under test	4
4 Wiring diagram	4
5 Test setup	4
6 Operating mode	4
7 Abbreviations used in this report	4
8 Rapid transient immunity tests in bursts on supply circuits	6
8.1 Test conditions	6
8.2 Test results	6
8.2.1 On power ports	6
8.2.2 On I/O signal, data and control ports	6
9 Rapid transient immunity tests in bursts on lines and terminals	7
9.1 Test conditions	7
9.2 Test results	7
9.2.1 On I/O signal, data and control ports	7
10 Surge test immunity on circuits	8
10.1 Common mode test conditions	8
10.2 Test results	8
10.3 Differential mode test conditions	8
10.4 Test results	8
11 Surge test immunity on on lines and terminals	9
11.1 Test conditions	9
11.2 Surge test on lines and terminals	9
12 Electrostatic discharge immunity tests	10
12.1 Indirect contact discharges	10
12.1.1 Test conditions	10
12.1.2 Test results	10
12.2 Direct discharges	11
12.2.1 Test conditions	11
12.2.2 Test results	11
13 Radiated, radio-frequency, electromagnetic field immunity test	12
13.1 Test conditions	12
13.2 Test results	12

14 Immunity to conducted disturbances, induced by radio-frequency fields	13
14.1 Test conditions	13
14.2 test results	13
15 Voltage variations immunity tests	14
15.1 Test conditions	14
15.2 Test results	14
16 Voltage dips, short interruptions immunity tests	15
16.1 Test conditions	15
16.2 Test results	15
17 Radiated emission measurements	16
17.1 Test conditions	16
17.2 Test results	16
18 Conducted emission measurements	18
18.1 Test conditions	18
18.2 Test results	18
19 Summary of test results and compliance notice	20
20 Internal and external photographs of the EUT	21
21 Test photographs	28

1 Purpose

The following test report presents all the results obtained at assesment test on .

2 List of standards and tests performed

Based on product standards :

EN 50130-4: 2011

Test standards:

EN 61000-4-2: 2009,
 EN 61000-4-3: 2006 / A1 : 2008 / A2 : 2010,
 EN 61000-4-4: 2012,
 EN 61000-4-5: 2014 / A1 : 2017 ,
 EN 61000-4-6: 2014,
 EN 61000-4-11: 2004 / A1: 2017,
 EN 55022:2010
 EN 61000-3-2: 2014
 EN 61000-3-3: 2013

Radio standards:

ETSI EN 301 489-1 (1.9.2),
 ETSI EN 301 489-3 (2.1.1)

Tests	Procedure	Severity of levels	
Immunity tests			
1. Repetitive electrical fast transients	EN 61000-4-4	2 kV on main; 1 kV on other circuits	A
2. Surge immunity test	EN 61000-4-5	2kV on main; 1kV on other circuits	A
3. Electrostatic discharge	EN 61000-4-2	8kV on the air; 6kV contact	A
4. Radiated electromagnetic field	EN 61000-4-3	3V/m; 10V/m	A
5. Conducted disturbances	EN 61000-4-6	3V/m; 10V/m	A
6. Voltage dips and variations	EN 61000-4-11	60%, 200ms; 100%, 100ms	A
Emission measurements			
7. Radiated emissions	EN 55022	Within the limits	A
8. Conducted disturbances	EN 55022	Within the limits	A
Other emission measurements			
9. Harmonic current emissions	EN 61000-3-2	Within the limits	N/A
10. Voltage fluctuations and flicker	EN 61000-3-3	Within the limits	N/A

A: test case apply to the test object

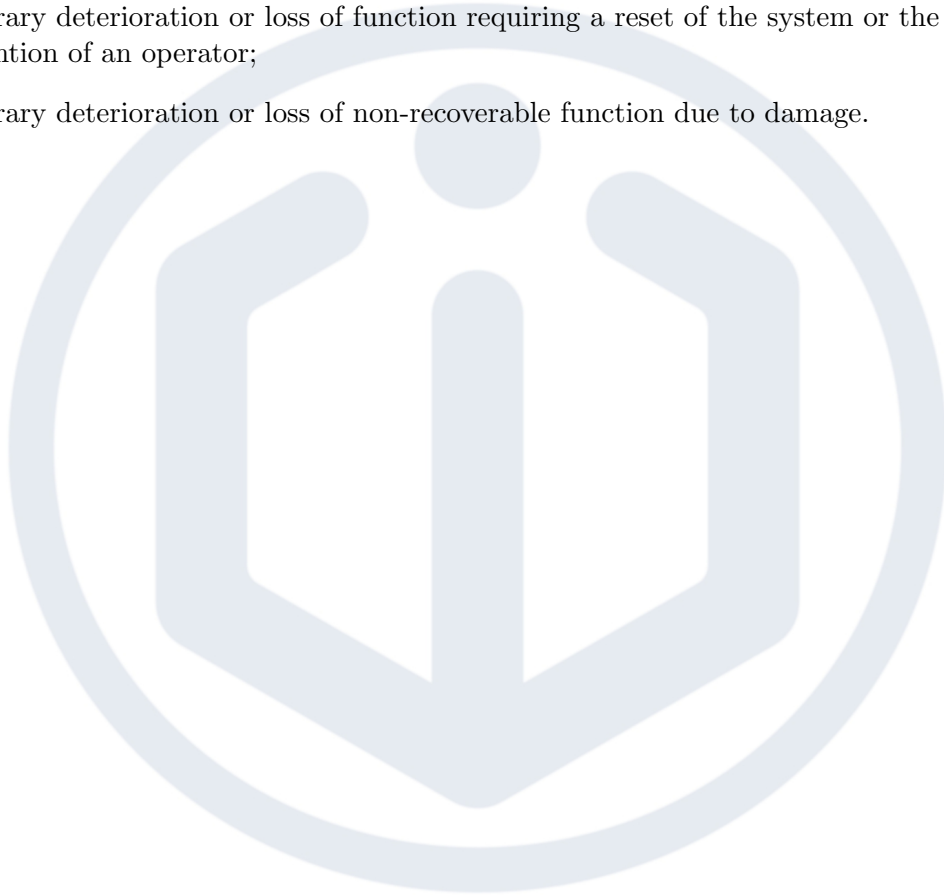
N/A : test case does not apply to the test object

N/R : No performed

F : Fail

Behavior criteria:

1. normal behavior ;
2. Temporary deterioration or self-recovering loss of function when the disturbance is removed ;
3. Temporary deterioration or loss of function requiring a reset of the system or the intervention of an operator;
4. Temporary deterioration or loss of non-recoverable function due to damage.



8 Rapid transient immunity tests in bursts on supply circuits

Standard : EN 61000-4-4

Test equipment: Haefely PEFT Junior

8.1 Test conditions

See wiring diagram.

t_m : 5ns

t_d : 50ns

Burts duration : 15ms

Period: 300ms

Test duration : 60s minimum

8.2 Test results

8.2.1 On power ports

Level	Voltage	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	C
3	+/- 2 kV	FC	1	C
X	+/- 3-4 kV	FC	1	C

8.2.2 On I/O signal, data and control ports

Level	Volatge	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	C
3	+/- 2 kV	FC	1	C
X	+/- 3 – 4 kV	FC	1	C

9 Rapid transient immunity tests in bursts on lines and terminals

Standard: EN 61000-4-4

Test equipment: Haefely PEFT Junior

Decoupling network: Haefely 093 506-1

9.1 Test conditions

See wiring diagram

Rising time: 5ns

Decreasing time: 50ns

Burst duration : 15ms

Period: 300ms

Test duration: 60s minimum

9.2 Test results

9.2.1 On I/O signal, data and control ports

Level	Voltage	remark	Behavior	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	C
3	+/- 2 kV	FC	1	C
X	+/- 3 – 4 kV	FC	1	C

10 Surge test immunity on circuits

Standard : EN 61000-4-5

Test equipment:

Proflin système SCHAFFNER

NSG 2050, PNW 2055

Surge wave : 8/20 μ s

10.1 Common mode test conditions

See wiring diagramm

Number of surges : 5 / phase angle

Delay between surges : 1 /mn

Source impedance : 12 Ohms

Coupling: L-PE; N-PE; L-N-PE

10.2 Test results

Class	Voltage	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	C
3	+/- 2 kV	FC	1	C
X	+/- 3 – 4 kV	FC	1	C

10.3 Differentiel mode test conditions

Number of surges : 5

Delay between surges: 1 /mn

Source impedance : 2 Ohms

10.4 Test results

Class	Voltage	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	C

11 Surge test immunity on on lines and terminals

Standard : EN 61000-4-5

Test equipment: Proflin système SCHAFFNER

NSG 2050 / PNW 2055

Surge wave: 8/20 μ s

Coupling network CDN 117, INA 170, INA 2055

11.1 Test conditions

See wiring diagram

Number of surges: 5

Delay between surges : 1 min

Source impedance : 2 ohms

Common mode: 40 Ohms + 0,5 μ F

11.2 Surge test on lines and terminals

Class	Voltage	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	C
3	+/- 2 kV	FC	1	C
X	+/- 3 kV – 4kV	FC	1	C

12 Electrostatic discharge immunity tests

12.1 Indirect contact discharges

Standard : EN 61000-4-2

Test equipment : Haefely PSB 25B

Cd+Cs =150pF ; Rd=330 Ohms

12.1.1 Test conditions

See wiring diagram

10 contact discharges per point on the horizontal plane

10 contact discharges per point on vertical plane

For test points location, refer §20

12.1.2 Test results

Discharges on horizontal plane

Points	Voltage	Remark	Result	Verdict
1-4	+/- 4 kV	FC	1	C
1-4	+/- 5 kV	FC	1	C
1-4	+/- 6 kV	FC	1	C
1-4	+/- 8 kV	FC	1	C

Discharges on vertical plane

Points	Voltage	remark	Result	Verdict
1-4	+/- 4 kV	FC	1	C
1-4	+/- 5 kV	FC	1	C
1-4	+/- 6 kV	FC	1	C
1-4	+/- 8 kV	FC	1	C

12.2 Direct discharges

12.2.1 Test conditions

See wiring diagram

10 contact discharges per point

10 discharges per point in the air

For test points location, refer §20

12.2.2 Test results

Air discharges

Points	Voltage	Remark	Results	verdict
1 à 5	+/- 4 kV	FC	1	C
1 à 5	+/- 8 kV	FC	1	C
1 à 5	+/- 12 kV	FC	1	C
1 à 5	+/- 15 kV	FC	1	C

Contact discharges

Points	Voltage	Remark	Result	Verdict
1 à 5	+/- 4 kV	FC	1	C
1 à 5	+/- 5 kV	FC	1	C
1 à 5	+/- 6 kV	FC	1	C
1 à 5	+/- 8 kV	FC	1	C

13 Radiated, radio-frequency, electromagnetic field immunity test

Standard : EN 61000-4-3

Test equipment :

SML02 ROHDE & SCHWARZ AmplifierWA1000

Antenne AS2 ; probe PCB

Probe H-fied: PR 1000

13.1 Test conditions

See wiring diagram

Severity : 3V/m ou 10V/m

Frequency range: 30MHz à 1Ghz

Modulation: 80% 1kHz sinusoïdal

13.2 Test results

Level	Remark	Result	Verdict
3 V/m	FC	1	C
10V/m	FC	1	C

14 Immunity to conducted disturbances, induced by radio-frequency fields

Standard : EN 61000-4-6

Test equipment:

SML02 ROHDE & SCHWARZ Amplificateur MRF 80

Coupling network: CDN 1 et attenuator - 6 dB

14.1 Test conditions

See wiring diagram

Level : 140 dB μ V / 10V rms ; 129.5 dB μ V / 3V rms

Frequency range : balayage de 0.15 MHz à 80 MHz

Modulation: 80 % 1kHz sinusoïdal

Pulse modulation: 1Hz 0.5s ON; 0.5s OFF

14.2 test results

Level	Remark	Result	Verdict
140dB μ V	FC	1	C

15 Voltage variations immunity tests

Standard : EN 61000-4-11

Test equipment: 108-TMX SCHAFFNER

Driven by: NSG 1006

15.1 Test conditions

See wiring diagram

Level: 230V +10%, 230 V - 15%

15.2 Test results

Level	Duration	Remark	Result	Verdict
+10%	10 s	FC	1	C
-15%	10 s	FC	1	C

16 Voltage dips, short interruptions immunity tests

Standard : EN 61000-4-11

Test equipment: 108-TMX SCHAFFNER

Driven by: NSG 1006

16.1 Test conditions

See wiring diagram

Applied on main supply voltage circuit

Duration of voltage shorts: 10 ; 20 ; 100 ; 200 ms

Duration of voltage dips: 10 ; 20 ; 100 ms

Number of voltage fluctuations: 3 /durée

Delay between fluctuations : 10s

16.2 Test results

Level	Duration	Remark	Result	Verdict
60%	0,5; 1;5;10 periods	FC	1	C
100%	0,5; 1; 5 periods	FC	1	C

17 Radiated emission measurements

Standard : EN 55022 Classe B

Test equipment: xxxxxxxxxxxxxxxxxxxx xxxxxxxxxxxxxxxxxxxxxxxx

17.1 Test conditions

See wiring diagram

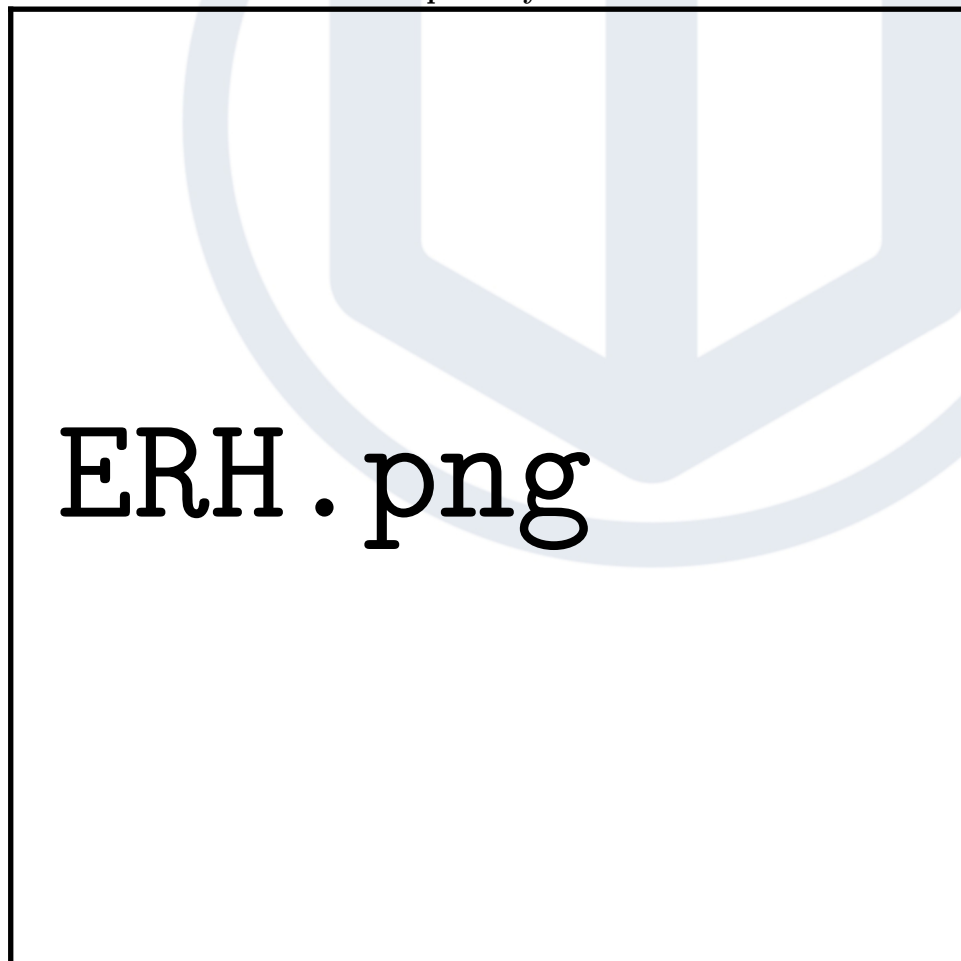
Bandwith : 120kHz

Frequency range : 30MHz – 1GHz

17.2 Test results

Level	Polarity	Remark	Verdict
Voir graphe	Horizontale	1	C
Voir graphe	Verticale	1	C

Measurements in horizontal polarity



Measurements in vertical polarity



ERV . png

18 Conducted emission measurements

Standard : 55022 Classe B

Test equipment: *****

18.1 Test conditions

See wiring diagram

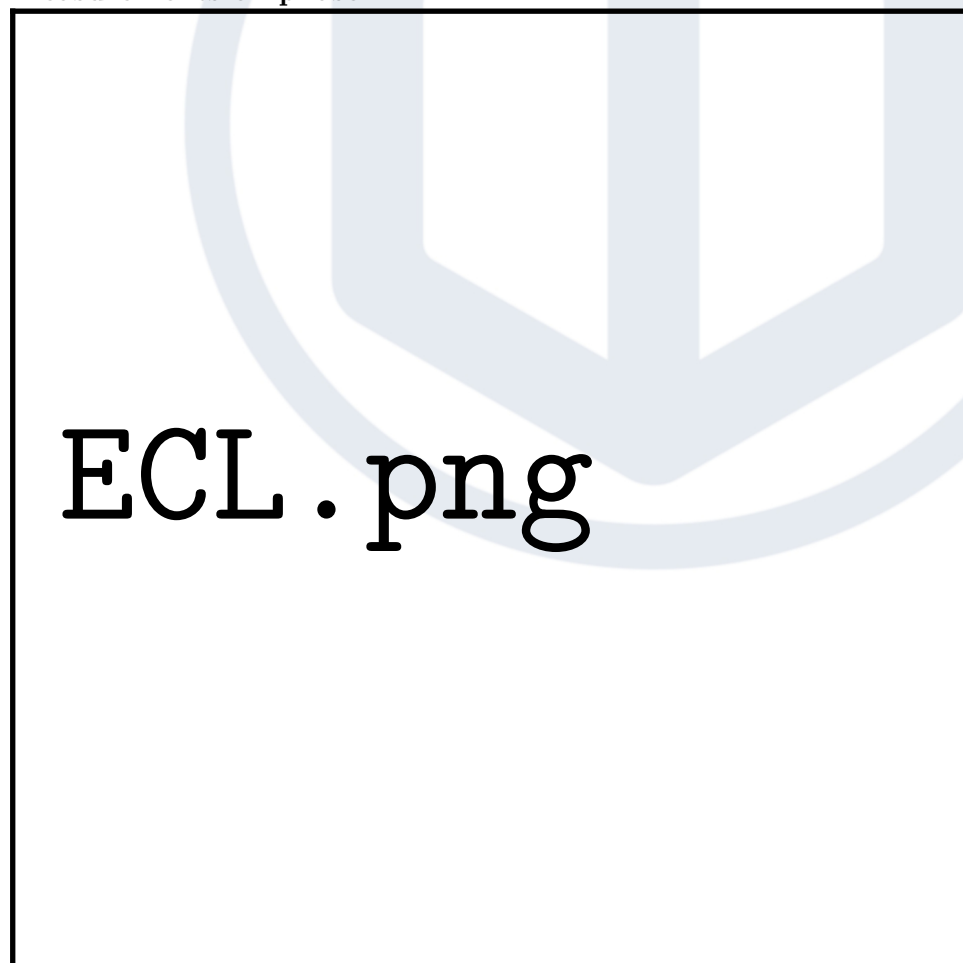
Bandwith: 9 kHz

Frequency range: 0.15 MHz – 30 MHz

18.2 Test results

Level	Polarity	Remark	Verdict
See graph	Phase	1	C
See graph	Neutral	1	C

Measurements on phase



Measurements on neutral



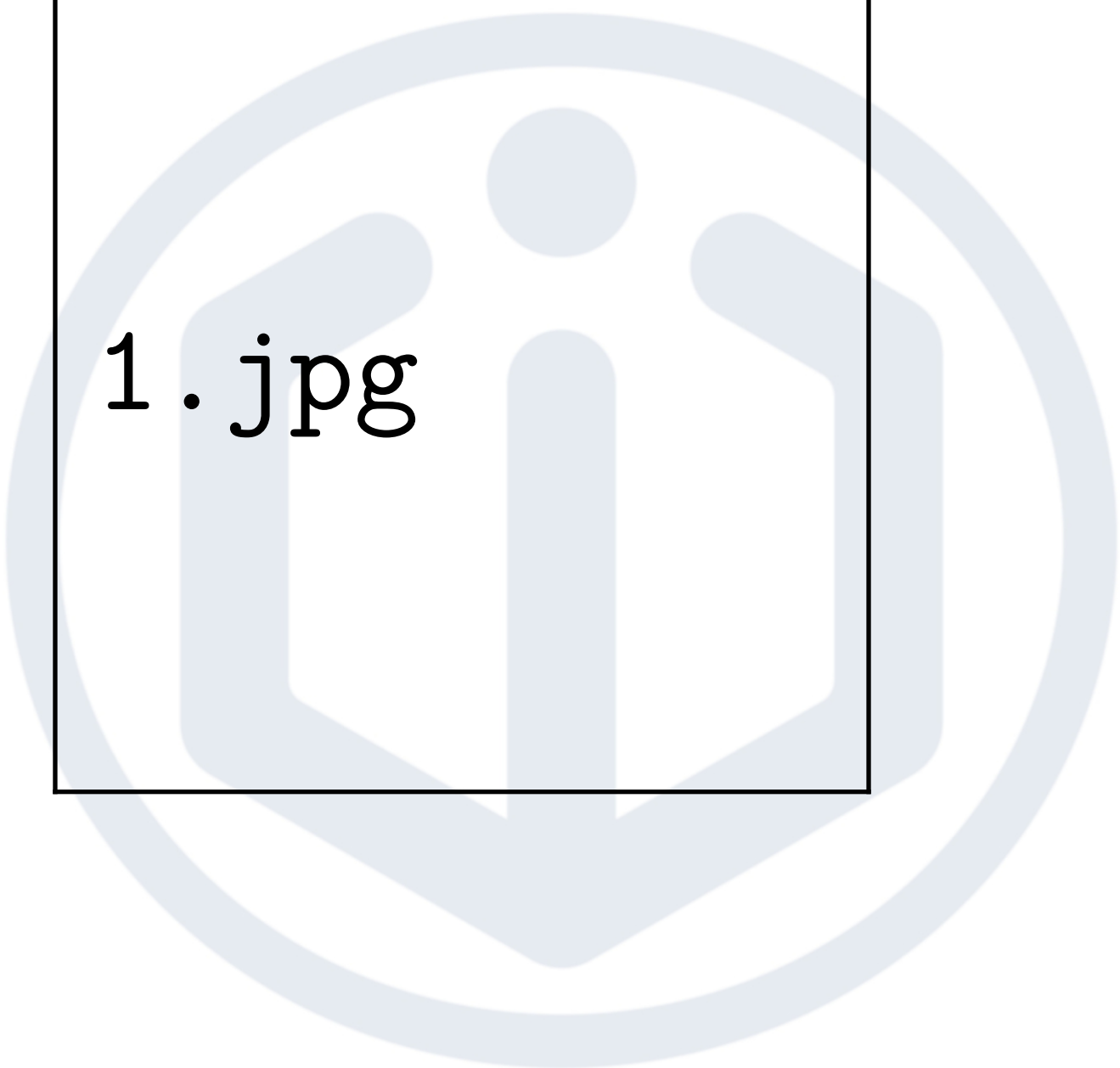
ECN . png

19 Summary of test results and compliance notice

Test	Procedure	Result
Immunity tests		
1. Repetitive electrical fast transients	EN 61000-4-4	C
2. Surge immunity test	EN 61000-4-5	C
3. Electrostatic discharge	EN 61000-4-2	C
4. Radiated electromagnetic field	EN 61000-4-3	C
5. Conducted disturbances	EN 61000-4-6	C
6. Voltage dips and variations	EN 61000-4-11	C
Emission measurements		
7. Radiated emissions	EN 55022	C
8. Conducted disturbances	EN 55022	C
Other emission measurements		
9. Harmonic current emissions	EN 61000-3-2	N/A
10. Voltage fluctuations and flicker	EN 61000-3-3	N/A

Le complies with european directive 2014/30/UE.

20 Internal and external photographs of the EUT



1.jpg



11.jpg



12.jpg

Fig 1 – Photos du clavier PROFIL100EC



2.jpg

Fig 2 – Boitier électronique déporté

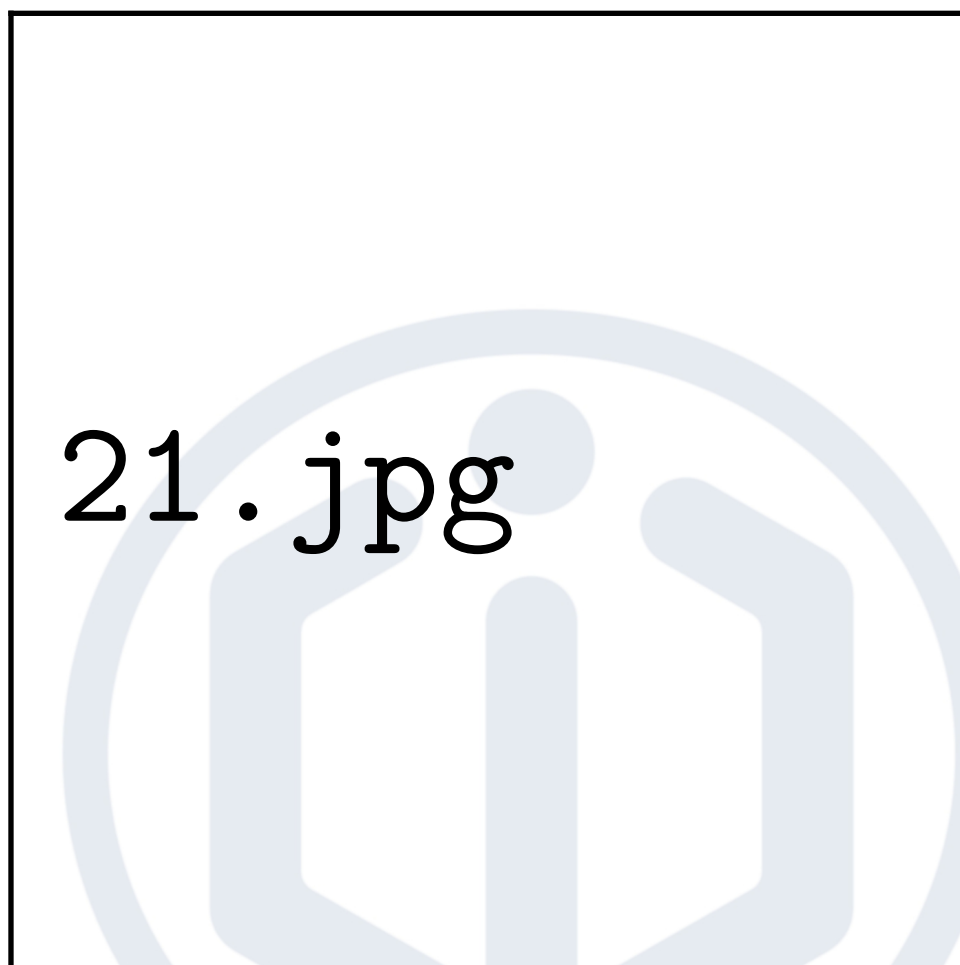


Fig 3 – Carte électronique dans le boîtier déporté



22.jpg

Fig 4 – Carte électronique face composants



23 . jpg

Fig 5 – Carte électronique face soudures

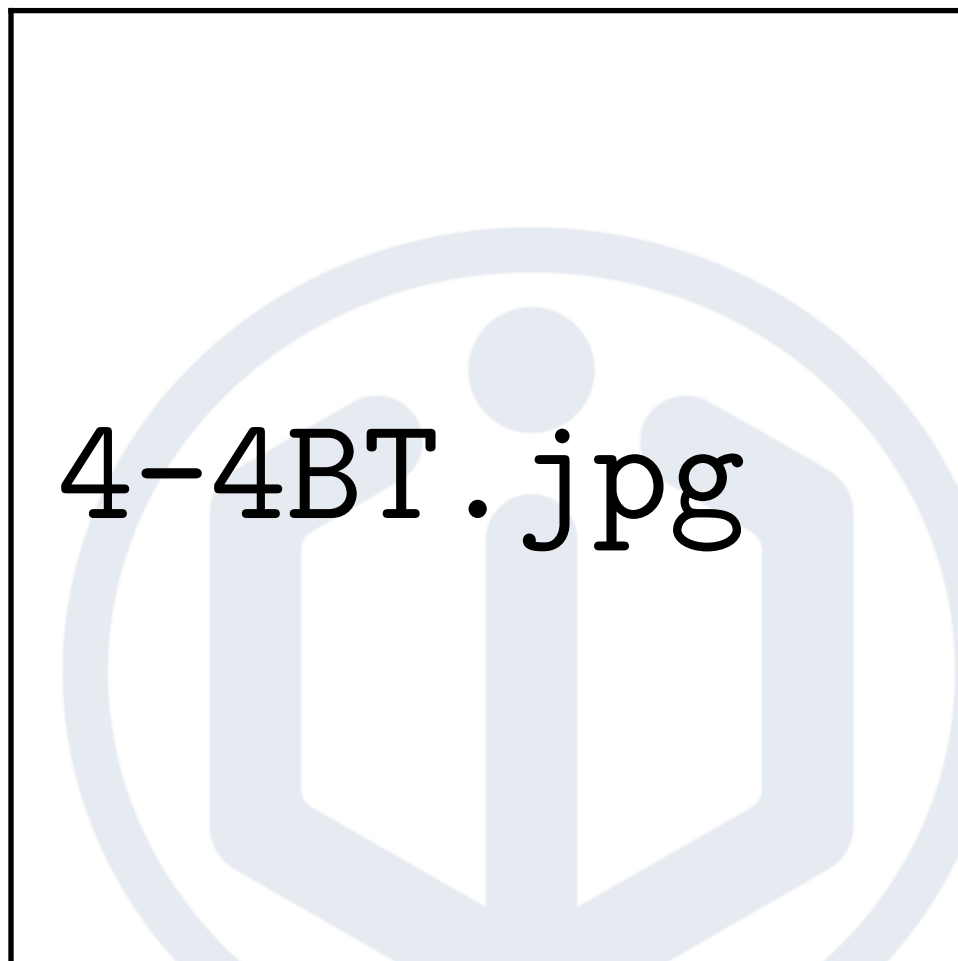


Fig 6 – Repetitive electrical fast transients test immunity on primary circuits



55C.jpg

Fig 7 – Conducted emissions measurement



4-2.jpg

Fig 8 – Electrostatic discharge test immunity

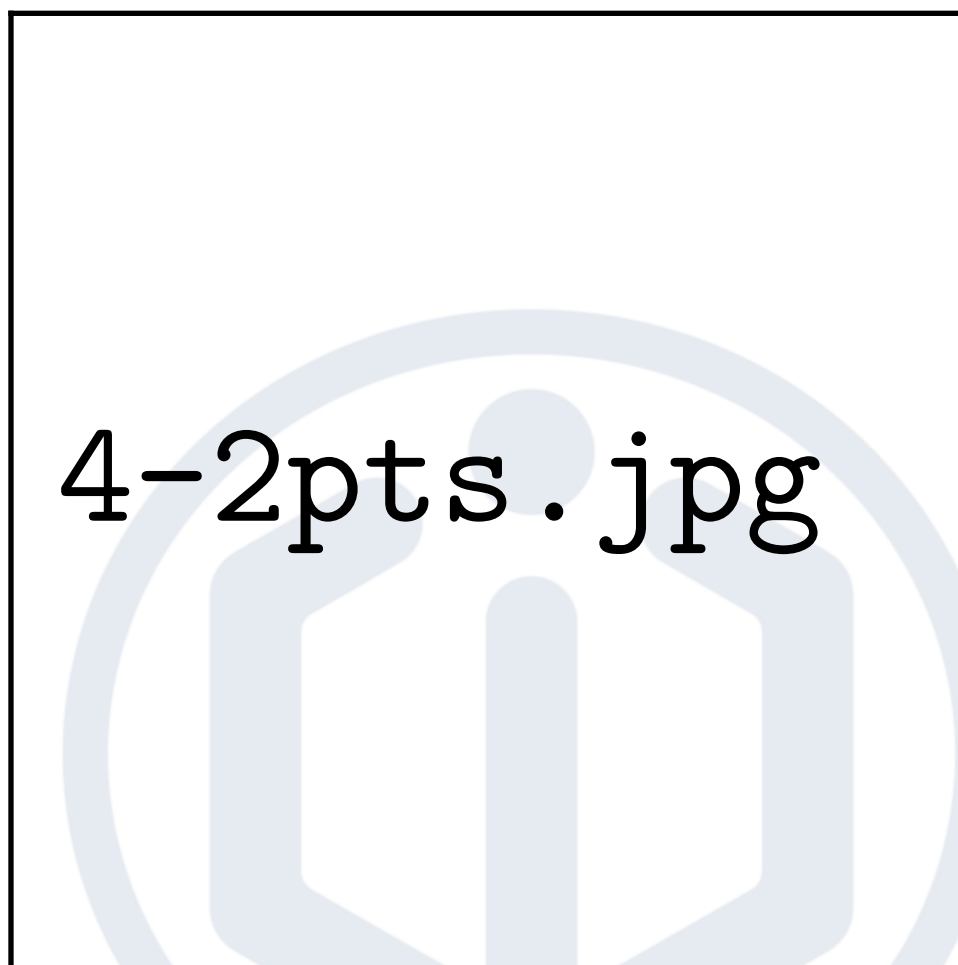


Fig 9 – Test points location for Electrostatic discharge test immunity

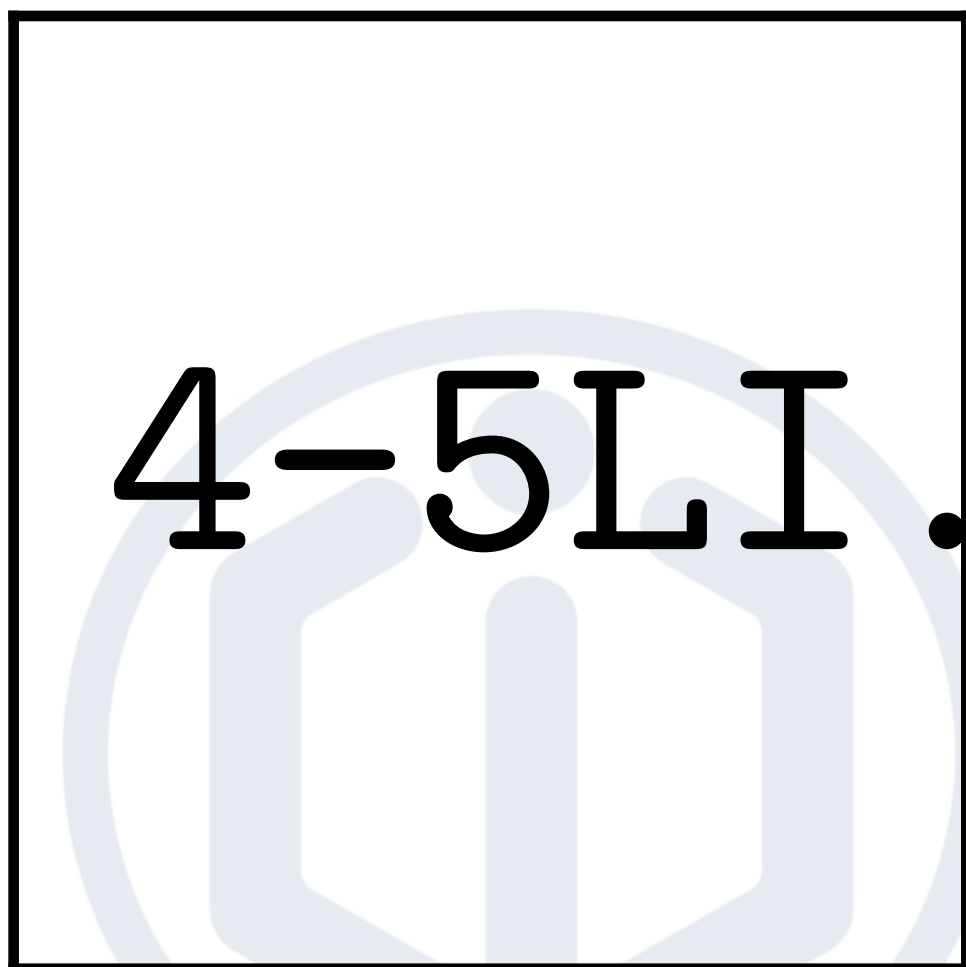


Fig 11 – Surge immunity test on I/O ports and terminals

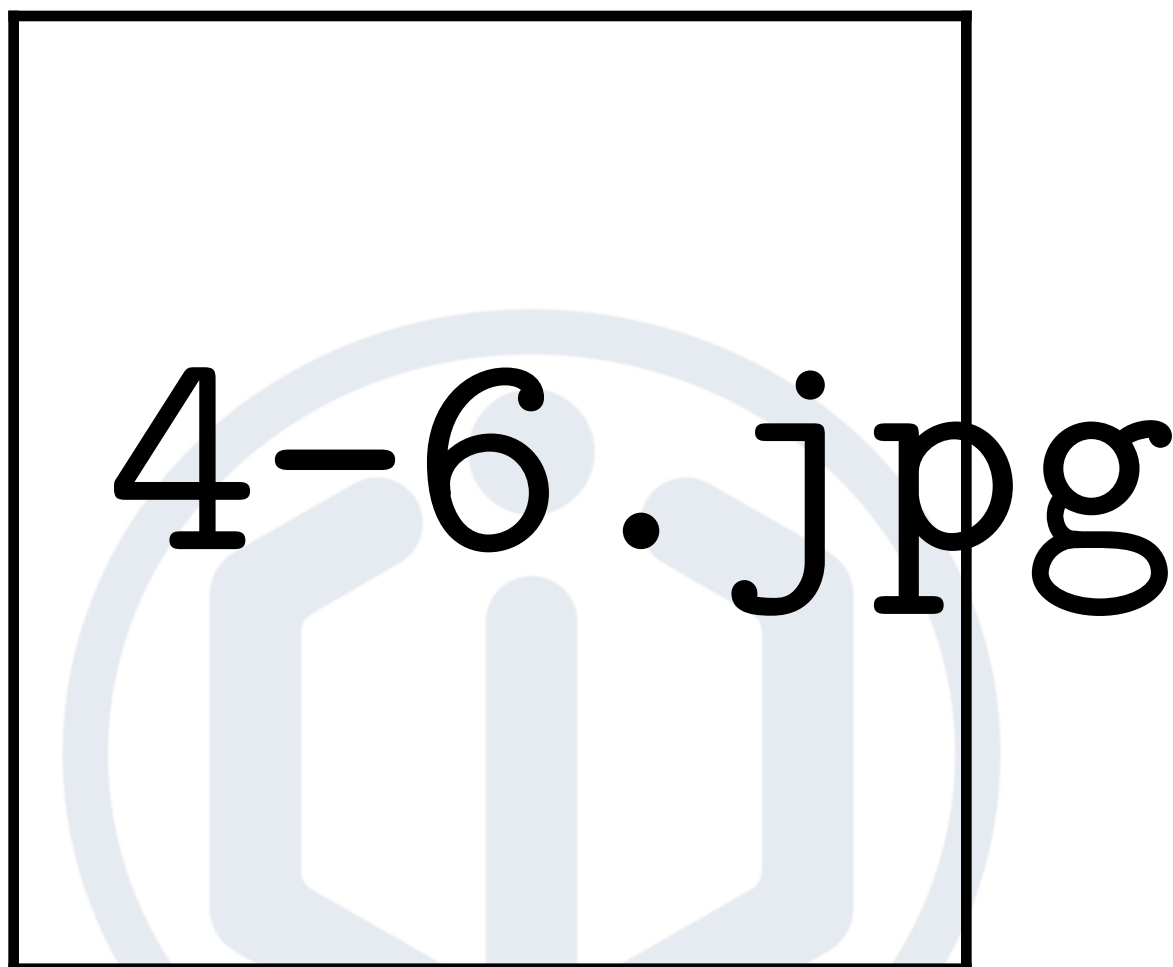


Fig 12 – Conducted disturbances, induced by radio-frequency fields immunity test

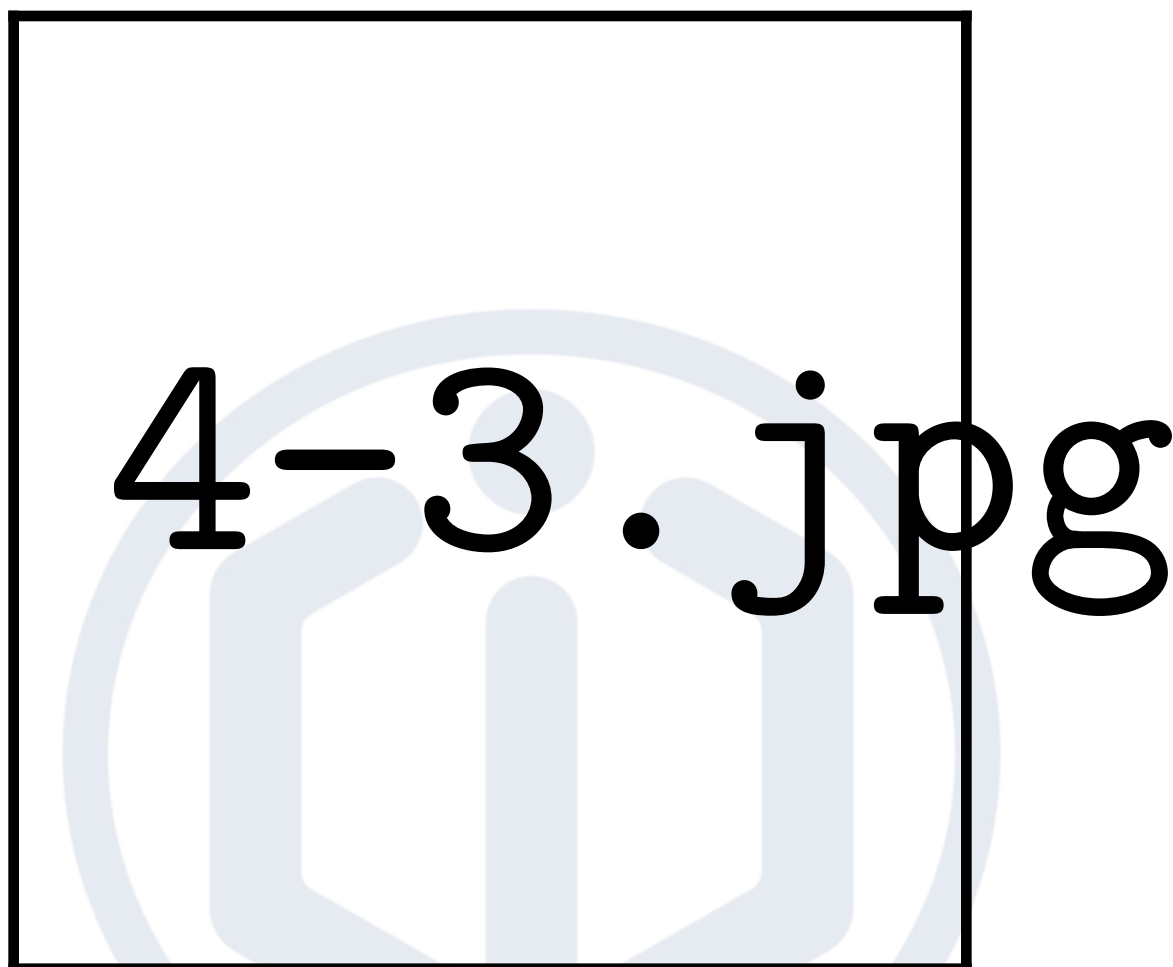


Fig 13 – Radiated, radiofrequency, electromagnetic field immunity test